FILE 'HOME' ENTERED AT 16:29:09 ON 08 APR 2003

=> file reg

COST IN U.S. DOLLARS ,

SINCE FILE ENTRY

TOTAL SESSION

FULL ESTIMATED COST

0.21

0.21

FILE 'REGISTRY' ENTERED AT 16:29:18 ON 08 APR 2003 USE IS SUBJECT TO THE TERMS OF YOUR STN CUSTOMER AGREEMENT. PLEASE SEE "HELP USAGETERMS" FOR DETAILS. COPYRIGHT (C) 2003 American Chemical Society (ACS)

Property values tagged with IC are from the ZIC/VINITI data file provided by InfoChem.

STRUCTURE FILE UPDATES: 7 APR 2003 HIGHEST RN 502131-66-0 DICTIONARY FILE UPDATES: 7 APR 2003 HIGHEST RN 502131-66-0

TSCA INFORMATION NOW CURRENT THROUGH MAY 20, 2002

Please note that search-term pricing does apply when conducting  ${\tt SmartSELECT}$  searches.

Crossover limits have been increased. See HELP CROSSOVER for details.

Experimental and calculated property data are now available. See HELP PROPERTIES for more information. See STNote 27, Searching Properties in the CAS Registry File, for complete details: http://www.cas.org/ONLINE/STN/STNOTES/stnotes27.pdf

=> ....Testing the current file.... screen

ENTER SCREEN EXPRESSION OR (END):end

=> screen 2067

L1 SCREEN CREATED

=>

Uploading C:\Program Files\Stnexp\Queries\09901657-b.str

L2 STRUCTURE UPLOADED

=> que L2 AND L1

L3 QUE L2 AND L1

=> d

L3 HAS NO ANSWERS

L1 SCR 2067

L2

STR

SEARCH

 $\bar{\mathcal{Q}}$ 

L5 ANSWER 1 OF 1 REGISTRY COPYRIGHT 2003 ACS

RN 129-64-6 REGISTRY

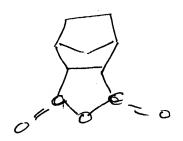
CN 4,7-Methanoisobenzofuran-1,3-dione, 3a,4,7,7a-tetrahydro-, (3aR,4S,7R,7aS)-rel- (9CI) (CA INDEX NAME)

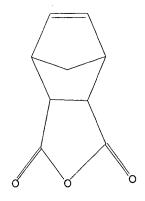
OTHER CA INDEX NAMES:

CN 4,7-Methanoisobenzofuran-1,3-dione, 3a,4,7,7a-tetrahydro-, (3a.alpha.,4.alpha.,7.alpha.,7a.alpha.)-; 5-Norbornene-2,3-dicarboxylic anhydride, cis-endo- (8CI)

OTHER NAMES:

5-Norbornene-endo-2,3-dicarboxylic anhydride; Bicyclo[2.2.1hept-5-ene-2endo, 3-endo-dicarboxylic anhydride; Bicyclo[2.2.1]-2-heptene-endo-5,6dicarboxylic acid anhydride; Bicyclo[2.2.1]hept-5-ene-2,3-dicarboxylic acid endo-cis-anhydride; Carbic anhydride; cis-3,6-endo-Methylene-1,2,3,6-tetrahydrophthalic anhydride; cis-5-Norbornene-endo-2,3dicarboxylic anhydride; Endic anhydride; endo,cis-5-Norbornene-2,3dicarboxylic anhydride; endo-3,6-Methylene-1,2,3,6-tetrahydrophthalic anhydride; endo-3,6-Methylene-4-cyclohexene-1,2-dicarboxylic anhydride; endo-5-Norbornene-2,3-dicarboxylic anhydride; endo-Bicyclo[2.2.1]hept-2ene-5,6-dicarboxylic anhydride; endo-Bicyclo[2.2.1]hept-5-ene-2,3dicarboxylic anhydride; endo-cis-3,6-endo-Methylene-.DELTA.4tetrahydrophthalic anhydride; endo-cis-Bicyclo[2.2.1]hept-5-ene-2,3dicarboxylic anhydride; endo-cis-Bicyclo[2.2.1]hept-5-ene-2,3dicarboxylic acid anhydride; endo-Himic acid anhydride; endo-Norbornene-2,3-dicarboxylic acid anhydride; Kayahard CD; Nadic acid anhydride; Nadic anhydride





Structure attributes must be viewed using STN Express query preparation. L3 QUE ABB=ON PLU=ON L2 AND L1

50 ANSWERS

=> s 13 sss sam
SAMPLE SEARCH INITIATED 16:29:41 FILE 'REGISTRY'
SAMPLE SCREEN SEARCH COMPLETED - 1404 TO ITERATE

71.2% PROCESSED 1000 ITERATIONS INCOMPLETE SEARCH (SYSTEM LIMIT EXCEEDED) SEARCH TIME: 00.00.01

FULL FILE PROJECTIONS: ONLINE \*\*COMPLETE\*\*

BATCH \*\*COMPLETE\*\*

PROJECTED ITERATIONS: 25833 TO 30327 PROJECTED ANSWERS: 1205 TO 2333

L4 50 SEA SSS SAM L2 AND L1

=> ....Testing the current file.... screen

ENTER SCREEN EXPRESSION OR (END):end

=> screen 970 AND 2067

L5 SCREEN CREATED

=>

Uploading C:\Program Files\Stnexp\Queries\09901657-a.str

L6 STRUCTURE UPLOADED

=> que L6 AND L5

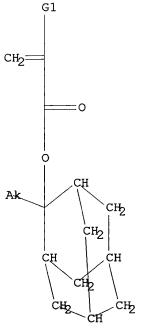
L7 QUE L6 AND L5

=> d

L7 HAS NO ANSWERS

L5 SCR 970 AND 2067

L6 STR



G1 H, Me

Structure attributes must be viewed using STN Express query preparation. L7 QUE ABB=ON PLU=ON L6 AND L5

=> s 17 sss sam

SAMPLE SEARCH INITIATED 16:30:58 FILE 'REGISTRY'
SAMPLE SCREEN SEARCH COMPLETED - 241 TO ITERATE

100.0% PROCESSED 24

241 ITERATIONS

48 ANSWERS

SEARCH TIME: 00.00.01

FULL FILE PROJECTIONS: ONLINE \*\*COMPLETE\*\*

BATCH \*\*COMPLETE\*\*

PROJECTED ITERATIONS:

3889 TO 5751

PROJECTED ANSWERS:

545 TO 1375

L8 48 SEA SSS SAM L6 AND L5

=> ....Testing the current file.... screen

ENTER SCREEN EXPRESSION OR (END):end

=> screen 2067

L9 SCREEN CREATED

=>

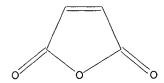
Uploading C:\Program Files\Stnexp\Queries\maleic anhydride.str

L10 STRUCTURE UPLOADED

=> que L10 AND L9

L11 QUE L10 AND L9

=> d L11 HAS NO ANSWERS L9 SCR 2067 L10 STR



Structure attributes must be viewed using STN Express query preparation. L11 QUE ABB=ON PLU=ON L10 AND L9

50 ANSWERS

=> s l11 sss sam SAMPLE SEARCH INITIATED 16:31:52 FILE 'REGISTRY' SAMPLE SCREEN SEARCH COMPLETED - 3510 TO ITERATE

28.5% PROCESSED 1000 ITERATIONS INCOMPLETE SEARCH (SYSTEM LIMIT EXCEEDED) SEARCH TIME: 00.00.01

FULL FILE PROJECTIONS: ONLINE \*\*COMPLETE\*\*
BATCH \*\*COMPLETE\*\*

PROJECTED ITERATIONS: 66648 TO 73752 PROJECTED ANSWERS: 55234 TO 61718

L12 50 SEA SSS SAM L10 AND L9

=> ....Testing the current file.... screen

ENTER SCREEN EXPRESSION OR (END):end

=> screen 970 AND 1015 AND 2067

L13 SCREEN CREATED

=>
Uploading C:\Program Files\Stnexp\Queries\allyltrimethylsilane.str

L14 STRUCTURE UPLOADED

=> que L14 AND L13

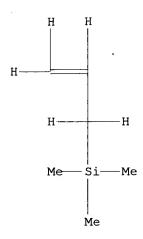
L15 QUE L14 AND L13

=> d

L15 HAS NO ANSWERS

L13 SCR 970 AND 1015 AND 2067

L14 STR



Structure attributes must be viewed using STN Express query preparation. QUE ABB=ON PLU=ON L14 AND L13 L15

 $\Rightarrow$  s 115 sss sam SAMPLE SEARCH INITIATED 16:32:28 FILE 'REGISTRY' SAMPLE SCREEN SEARCH COMPLETED - 204 TO ITERATE

100.0% PROCESSED 204 ITERATIONS 11 ANSWERS

SEARCH TIME: 00.00.01

FULL FILE PROJECTIONS: ONLINE \*\*COMPLETE\*\*

BATCH \*\*COMPLETE\*\*

PROJECTED ITERATIONS:

3224 TO

PROJECTED ANSWERS:

22 TO 418

11 SEA SSS SAM L14 AND L13

=> s 14 and 18 and 112 and 116 O L4 AND L8 AND L12 AND L16 L17

=> FIL CAPLUS HCAPLUS USPATFUL COST IN U.S. DOLLARS

SINCE FILE TOTAL SESSION ENTRY

FULL ESTIMATED COST

2.61 2.40 FILE 'CAPLUS' ENTERED AT 16:32:50 ON 08 APR 2003

USE IS SUBJECT TO THE TERMS OF YOUR STN CUSTOMER AGREEMENT. PLEASE SEE "HELP USAGETERMS" FOR DETAILS. COPYRIGHT (C) 2003 AMERICAN CHEMICAL SOCIETY (ACS)

FILE 'HCAPLUS' ENTERED AT 16:32:50 ON 08 APR 2003 USE IS SUBJECT TO THE TERMS OF YOUR STN CUSTOMER AGREEMENT. PLEASE SEE "HELP USAGETERMS" FOR DETAILS. COPYRIGHT (C) 2003 AMERICAN CHEMICAL SOCIETY (ACS)

FILE 'USPATFULL' ENTERED AT 16:32:50 ON 08 APR 2003 CA INDEXING COPYRIGHT (C) 2003 AMERICAN CHEMICAL SOCIETY (ACS)

=> s 14 and 18 and 112 and 116 0 L4 AND L8 AND L12 AND L16 => s 117

0 L17 L19

=> s 14

L20 143 L4

=> s 18

L21 176 L8

=> s 112

L22 143 L12

=> s 116

28 L16 L23

=> s (120 or 122)

L24 284 (L20 OR L22)

=> s 124 and 121 and 123

0 L24 AND L21 AND L23

=> s 124 and 121

L26 34 L24 AND L21

=> s 124 and 123

L27 0 L24 AND L23

=> s 121 and 123

L28 4 L21 AND L23

=> s 126 or 128

L29 38 L26 OR L28

=> duplicate

ENTER REMOVE, IDENTIFY, ONLY, OR (?):remove

ENTER L# LIST OR (END):129

DUPLICATE PREFERENCE IS 'CAPLUS, HCAPLUS, USPATFULL'

KEEP DUPLICATES FROM MORE THAN ONE FILE? Y/(N):n

PROCESSING COMPLETED FOR L29

20 DUPLICATE REMOVE L29 (18 DUPLICATES REMOVED)

=> d 130 1-20 ibib hitstr abs

L30 ANSWER 1 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 1

ACCESSION NUMBER: 2003:20986 CAPLUS

138:98194

DOCUMENT NUMBER: TITLE:

Positive photosensitive composition

INVENTOR(S):

Fujimori, Toru

PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan

Eur. Pat. Appl., 135 pp. SOURCE:

CODEN: EPXXDW

DOCUMENT TYPE:

Patent

LANGUAGE:

English

FAMILY ACC. NUM. COUNT: 1

PATENT INFORMATION:

PATENT NO. KIND DATE APPLICATION NO. DATE

EP 1273970 A2 20030108 EP 2002-14889 20020705

R: AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT, IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, SK JP 2003021905 A2 20030124 JP 2001-206637 20010706

JP 2003098672 A2 20030404 JP 2001-287112 20010920 JP 2003084441 A2 20030319 JP 2002-196113 20020704 A 20010705 PRIORITY APPLN. INFO.: JP 2001-204969 JP 2001-206637 · A 20010706 A 20010920 JP 2001-287112

IT 398140-71-1P 398140-88-0P 398141-14-5P

RL: PRP (Properties); SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses) (pos. photosensitive compn. contg.)

RN 398140-71-1 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

CM 2

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

$$0 - C - CH = CH_2$$

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM -

CRN 79-10-7 CMF C3 H4 O2

AB A pos. photosensitive compn. comprises (A) an acid generator that generates an acid upon irradn. of an actinic ray or radiation, (B) a resin that has a monocyclic or polycyclic alicyclic hydrocarbon structure and is decompd. by the action of an acid to increase soly. in an alkali developing soln., and (C) a specific basic compd. The present invention relates to a pos. photosensitive compn. used in the prodn. process of semiconductor devices and in other photofabrication processes. The present invention relates to a pos. photosensitive compn. suitable for use a far UV ray of .ltoreq. 250 nm as a light source for exposure.

L30 ANSWER 2 OF 20 CAPLUS COPYRIGHT 2003 ACS

DUPLICATE 2

ACCESSION NUMBER:

2002:904532 CAPLUS

DOCUMENT NUMBER:

137:391087

TITLE:

Positive-working photoresist compositions containing

specific resin and specific acid-generator

INVENTOR(S):
PATENT ASSIGNEE(S):

Sato, Kenichiro; Kodama, Kunihiko Fuji Photo Film Co., Ltd., Japan

SOURCE:

Jpn. Kokai Tokkyo Koho, 105 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND	DATE		APPLICATION N	ο.	DATE
JP 2002341539	<b>A</b> 2	20021127		JP 2001-14962	0	20010518
US 2003008241	A1	20030109		US 2002-93411		20020311
PRIORITY APPLN. INFO.	:		JP	2001-68849	Α	20010312
			JP	2001-68850	Α	20010312
			JP	2001-149620	Α	20010518

## IT 398140-88-0P 398141-14-5P

RL: SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(resin; pos.-working photoresist compns.)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

GI

AB The title compn. contains a resin increasing the soly. towards an alkali developer by reacting with an acid and actinic ray- or radiation-sensitive acid-generator, wherein the resin has repeating unit I(R11'-12' = H, cyano, halo, alkyl; Z' = alicyclic residue), repeating unit II ( Z2 = -O-, -N(R41)-; R41 = H, OH, alkyl, etc.), and [CH2-C(R91)(-CO-X-Q-R92)] ( R91= H, lower alkyl, halo, CN; X5 = -O-, -S-, -NR93-, -NR93SO2-; R93 = H, alkyl; Q = single bond, connecting group) and wherein the acid-generator has structure (R1)(R2)(R3)S+ X- or R4-I+-R5 X- ( R1-5 = aliph. hydrocarbon, arom. hydrocarbon; X- = R6-SO2-N--SO2=R7,

R8-SO2-C-(SO2-R10)-SO2-R9; R6-10 = aliph. hydrocarbon). The compn. provides the photoresist of the high resoln. and the wide margin for the exposure conditions for.

L30 ANSWER 3 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 3

ACCESSION NUMBER:

2002:848227 CAPLUS

DOCUMENT NUMBER:

137:360309

TITLE:

Radiation-sensitive positive resist compositions showing wide defocus latitude and less particle

generation on storage

INVENTOR(S):

Kodama, Kunihiko; Sato, Kenichiro Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 90 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

SOURCE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT ASSIGNEE(S):

PATENT NO.	KIND	DATE		APPLICATION N	10.	DATE
JP 2002323767	<b>A</b> 2	20021108		JP 2001-15736	56	20010525
US 2003017415	A1	20030123		US 2002-79414	1	20020222
PRIORITY APPLN. INFO.	:		JP	2001-48602	Α	20010223
			JP	2001-48783	Α	20010223
			JP	2001-48784	Α	20010223
		1	JP	2001-48880	Α	20010223
		•	JP	2001-157366	Α	20010525
			.TP	2001-157367	Α	20010525

## IT 398140-88-0P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(radiation-sensitive pos. resist compns. showing wide defocus latitude and less particle generation on storage)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

## IT 398140-71-1 398141-14-5

RL: TEM (Technical or engineered material use); USES (Uses) (radiation-sensitive pos. resist compns. showing wide defocus latitude and less particle generation on storage)

RN 398140-71-1 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

AB The compns., esp. suited for deep-UV lithog., comprise acid generators contg. triarylsulfonium salts and phenathylsulfonium salts, alicyclic hydrocarbon resins increasing alkali soly. upon reaction with acids, bases, and fluoro and/or silicone surfactants,. The compns. may contain OH-bearing and -free solvent mixts.

L30 ANSWER 4 OF 20 CAPLUS COPYRIGHT 2003 ACS

DUPLICATE 4

ACCESSION NUMBER:

2002:848220 CAPLUS

DOCUMENT NUMBER:

137:360306

TITLE:

Radiation-sensitive positively working photosensitive

composition

INVENTOR(S):
PATENT ASSIGNEE(S):

Kodama, Kunihiko; Sato, Kenichiro Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 92 pp.

SOURCE:

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
~~~~~~				
JP 2002323758	A2	20021108	JP 2001-157367	20010525
US 2003017415	A1	20030123	US 2002-79414	20020222

JP 2001-48783 A 20010223
JP 2001-48602 A 20010223
JP 2001-48784 A 20010223
JP 2001-48880 A 20010223
JP 2001-157366 A 20010525
JP 2001-157367 A 20010525

## IT 398140-88-0P 398141-14-5P 474510-67-3P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(radiation-sensitive pos. working photosensitive compn. for high resoln. and storage stability)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

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CM 3

CRN 154970-45-3 CMF C12 H18 O2

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CRN 79-10-7 CMF C3 H4 O2

RN 474510-67-3 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 3-hydroxytricyclo[3.3.1.13,7]dec-1-yl ester, polymer with 1-bicyclo[2.2.1]hept-5-en-2-yl-2-methyl-2-(4-methylcyclohexyl)-1-propanone, 5-ethoxy-3a,4,5,6,7,7a-hexahydro-4,7-methano-1H-indene and 2,5-furandione (9CI) (CA INDEX NAME)

CM 1

CRN 474510-66-2 CMF C18 H28 O

CM 2

CRN 331866-92-3 CMF C18 H24 O3

CM 3

CRN 53018-26-1 CMF C12 H18 O

AB The compn. comprises (A) acid generator sensitive to actinic ray or radiation, (B) (poly)alicyclic hydrocarbon polymer which becomes alkali sol. by acid decompn., (C) basic compd., and (D) fluoro and/or silicone surfactant, where the acid generator contains .gtoreq.1 compd. having a phenacyl sulfonium salt structure and .gtoreq.1 nonarom. sulfonium salt. The compn. provides a photoresist having high resoln. and wide defocus latitude by exposure with a ring-shaped light source and a photoresist having good pattern profile by exposure with a half-tone phase-shift mask. Generation of particles under storage of the compn. is suppressed.

L30 ANSWER 5 OF 20 CAPLUS COPYRIGHT 2003 ACS

DUPLICATE 5

ACCESSION NUMBER:

2002:792710 CAPLUS

DOCUMENT NUMBER:

137:317922

TITLE:

Positive photoresist compositions offering sharp

patterns

INVENTOR(S):

Sato, Kenichiro

PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 85 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

SOURCE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO. KIND DATE APPLICATION NO. DATE

JP 2002303984 A2 20021018 JP 2001-135245 20010502
PRIORITY APPLN. INFO.: JP 2001-22010 A 20010130

OTHER SOURCE(S):

MARPAT 137:317922

TT 398140-71-1P 398140-88-0P 398141-14-5P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(pos. photoresist compns. offering sharp patterns)

RN 398140-71-1 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

$$\bigcirc \stackrel{\circ}{ \bigcirc } \circ$$

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2.

CRN 342648-11-7 CMF C13 H22 O2

3 CM

CRN 108-31-6 CMF C4 H2 O3

CM

79-10-7 CMF C3 H4 O2

AB The pos. photoresist compns. which give fine patterns with good profile, smoother line edges, and no top profile erosion for ArF excimer laser lithog. contain (A) resins which have alicyclic hydrocarbon groups and increase soly. speed to alkali developers by acids, (B) compds. which generate acids by actinic light or radiation, and (C) acetals shown as R1010CHMeOR102 or R102OCHMeOR102 (R101, R102 = alkyl which may have linear, branched, or cyclic substituents).

L30 ANSWER 6 OF 20 CAPLUS COPYRIGHT 2003 ACS

DUPLICATE 6

ACCESSION NUMBER:

2002:673047 CAPLUS

DOCUMENT NUMBER:

137:224108

TITLE:

Storage-stable excimer laser-sensitive

positive-working photosensitive compositions with

reduced pattern variation on defocusing

INVENTOR(S):

Kodama, Kunihiko; Sato, Kenichiro Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 86 pp.

SOURCE:

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT ASSIGNEE(S):

PATENT NO.	KIND	DATE		APPLICATION N	Ю.	DATE
JP 2002251012	· A2	20020906		JP 2001-48784	ļ	20010223
US 2003017415	A1	20030123		US 2002-79414		20020222
PRIORITY APPLN. INFO.	:		JP	2001-48602	Α	20010223
			JP	2001-48783	Α	20010223
			JP	2001-48784	A	20010223
			JP	2001-48880	Α	20010223
			JP	2001-157366	Α	20010525
			JP	2001-157367	Α	20010525
TT			D 4 1			

IT 398140-71-1P 398140-88-0P, tert-Butyl

norbornenecarboxylate-maleic anhydride-2-methyl-2-adamantyl acrylate-norbornenelactone acrylate copolymer 398141-14-5P

RL: PNU (Preparation, unclassified); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(chem. amplified storage-stable excimer laser-sensitive pos. photoresists with reduced pattern variation on defocusing)

RN 398140-71-1 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

CM 2

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF .C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CRN 79-10-7 C3 H4 O2 CMF

The compns. comprise (A) photoacid generators, (B) resins contg. alicyclic hydrocarbon structures, which increase their alkali soly. by acid decompn., (C) base compds., and (D) fluoro- and/or silicone-based surfactants, wherein the photoacid generator is a mixt. of triarylsulfonium salts and non-arom. sulfonium salts. The compns. are useful for chem. amplified photoresists suitable for halftone phase-shift masks.

L30 ANSWER 7 OF 20 CAPLUS COPYRIGHT 2003 ACS

ACCESSION NUMBER: 2002:673045 CAPLUS

DOCUMENT NUMBER:

137:224107

Chemically amplified positive-working far-UV TITLE:

photoresist compositions suitable for halftone

DUPLICATE 7

phase-shift masks

INVENTOR(S): Sato, Kenichiro; Uenishi, Kazuya Fuji Photo Film Co., Ltd., Japan PATENT ASSIGNEE(S): SOURCE:

Jpn. Kokai Tokkyo Koho, 104 pp.

CODEN: JKXXAF

DOCUMENT TYPE: Patent

LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

KIND DATE APPLICATION NO. PATENT NO. \_\_\_\_\_ JP 2002251011 A2 20020906 JP 2001-48782 20010223 PRIORITY APPLN. INFO.: JP 2001-48782 20010223

OTHER SOURCE(S): MARPAT 137:224107

398140-71-1P 398140-88-0P, tert-Butyl

norbornenecarboxylate-maleic anhydride-2-methyl-2-adamantyl acrylate-norbornenelactone acrylate copolymer 398141-14-5P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(chem. amplified pos.-working far-UV photoresists suitable for halftone phase-shift masks)

RN 398140-71-1 CAPLUS

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-CN tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CRN 398140-70-0 CMF C12 H14 O4

CM 2

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4

CRN 342648-11-7 CMF C13 H22 O2

CM 3

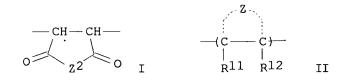
CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

$$\begin{matrix} \text{O} \\ || \\ \text{HO-C-CH} == \text{CH}_2 \end{matrix}$$

GI



$$(R^{60})_m 1$$
  $(OR^{61})_p 1$  III

The compns. comprise (A) polymers with acid-decomposable groups comprising AB repeating units CH(COXAR1)CH(COXAR2) (R1, R2 = H, cyano, OH, CO2H, etc.) and/or I (Z2 = 0, NR3; R3 = H, OH, alkyl, haloalkyl, etc.) and other repeating units II (R11, R12 = H, cyano, halo, alkyl; Z = at. group contg. C2 linkage for forming alicyclic structure), (B) dissoln. inhibitors R[X(CR51R52)q1CO2R']n1 (X = O, S, NR53, single linkage; R51-53 = H, alkyl; R' = acid-decomposable group as CO2R'; R = n1-valent residue of bridged hydrocarbon, satd. hydrocarbon, naphthalene; n1 = 1-4; q1 = 0-10) or III (R60 = alkyl, halo; R61 = acid-decomposable group as OR61; m1 = 0-4; p1 =1-4), and (C) imido sulfonate photoacid generators. The compns. may further contain sulfonium salt photoacid generators.

L30 ANSWER 8 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 8

ACCESSION NUMBER:

2002:592336 CAPLUS

DOCUMENT NUMBER:

137:147763

TITLE:

Chemically amplified positive-working photoresist

composition providing fine resolution patterns

INVENTOR(S):

Fujimori, Toru

PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 94 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

1

LANGUAGE:

SOURCE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
JP 2002221796	A2	20020809	JP 2001-18868	20010126
PRIORITY APPLN. INFO.	:	JP	2001-18868	20010126
OTHER SOURCE(S):	MA	RPAT 137:147763		

OTHER SOURCE(S):

398140-88-0P RL: IMF (Industrial manufacture); TEM (Technical or engineered material

use); PREP (Preparation); USES (Uses) (in chem. amplified pos.-working photoresist compn. for far-UV exposure)

RN 398140-88-0 CAPLUS

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid; 1,1-dimethylethyl ester, CN polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2Hcyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

249562-06-9 CMF C14 H20 O2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

IT 398141-14-5

RL: TEM (Technical or engineered material use); USES (Uses) (in chem. amplified pos.-working photoresist compn. for far-UV exposure)

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

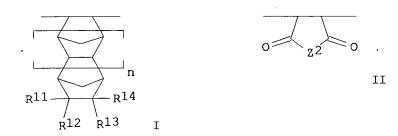
CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

GI



The photoresist compn., used in fabrication of semiconductor devices, AB contains a photoacid generator, a polymer increasing the soly. in an alkali developer by reaction with an acid and having repeating groups I, II, and III [R11-14 = acid-decomposable group, H, halo, cyano, CO2H, etc.; .gtoreq.2 of R11-14 may form a ring; n = 0, 1; Z2 = O, N(R41); R41 = H, OH, (halo)alkyl, etc.; R91 = H, lower alkyl, halo, CN; X5 = O, S, etc.; R92 = H, cyclic or chain alkyl, alkoxy, OH, etc.], and a compd. contg. CON(OH) group. The photoresist compn., esp. when using an ArF excimer laser, provides excellent post exposure delay (PED) stability and profiles and inhibits shortening of line pattern edges.

L30 ANSWER 9 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 9

ACCESSION NUMBER: 2002:566567 CAPLUS

DOCUMENT NUMBER: 137:132103

Positive-working photoresist composition TITLE:

Fujimori, Toru INVENTOR(S):

PATENT ASSIGNEE(S): Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 93 pp. SOURCE:

CODEN: JKXXAF

DOCUMENT TYPE: Patent LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO. KIND DATE APPLICATION NO. \_\_\_\_\_ JP 2002214787 20020731 JP 2001-13298 20010122 20010122 JP 2001-13298 PRIORITY APPLN. INFO.:

398140-88-0P 398141-14-5P

RL: SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(resin in pos.-working photoresist compn.)

RN 398140-88-0 CAPLUS

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, CN polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2Hcyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2yl 2-propenoate (9CI) (CA INDEX NAME)

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

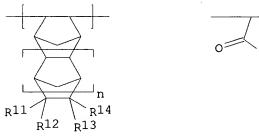
CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

GI



I

AB The title compn. contains a light- or radiation-sensitive acid generator, a resin increasing soly. rate in an alkali developer by an acid, and a compd. having an acid-sensitive group, wherein the resin has repeating group I(R11-14 = acid-sensitive group, H, halo, cyano, etc.; n = 0, 1), II( Z2 = -O-, -N(R41)-;R41 = H, OH, alkyl, etc.), and [CH2-C(R91)(CO-X5-B-R92)](R91= H, lower alkyl, halo, -CN; X5 = -O-, -S-, -NR93; R93 = H, chain or cyclic alkyl; B = single bond, connecting group; R92 = H, chain or cyclic alkyl, alkoxy, carboxy, etc.) and wherein the compd. having the acid-sensitive group generates a group, which is sol. in the alkali developer or more sol. in the alkali developer before the acid reaction. The compn. shows the improved stability during the post exposure delay(PED).

L30 ANSWER 10 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 10

ACCESSION NUMBER: 2002:566566 CAPLUS

DOCUMENT NUMBER: 137:132102

TITLE: Positive-working photoresist composition

INVENTOR(S): Fujimori, Toru

PATENT ASSIGNEE(S): Fuji Photo Film Co., Ltd., Japan SOURCE: Jpn. Kokai Tokkyo Koho, 78 pp.

CODEN: JKXXAF

DOCUMENT TYPE: Patent LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT: 1

PATENT INFORMATION:

## IT 398140-88-0P 398141-14-5P

RL: SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(resin in pos.-working photoresist compn.)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CRN 342648-11-7 CMF C13 H22 O2

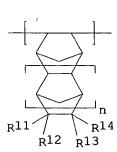
CM 3

CRN 108-31-6 CMF C4 H2 O3

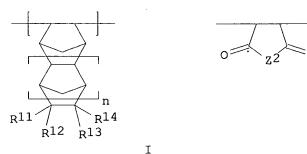
CM 4

CRN 79-10-7 CMF C3 H4 O2

GI



Ι



TT

The title compn. contains a light- or radiation-sensitive acid generator, AB a resin increasing soly. rate in an alkali developer by an acid, and a basic compd. not contg. an arom. group, wherein the resin has repeating group I(R11-14 = acid-sensitive group, H, halo, cyano, etc.; n = 0, 1), II( Z2 = -O-, -N(R41)-; R41 = H, OH, alkyl, etc.), and [CH2-C(R91)(CO-X5-B-R92)](R91= H, lower alkyl, halo, -CN; X5 = -O-, -S-, -NR93; R93 = H, chain or cyclic alkyl; B = single bond, connecting group; R92 = H, chain or cyclic alkyl, alkoxy, carboxy, etc.). The compn. shows the improved stability during the post exposure delay(PED).

L30 ANSWER 11 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 11

ACCESSION NUMBER: 2002:538441 CAPLUS

DOCUMENT NUMBER: 137:116950

TITLE: Chemically amplified far-UV positive photoresists

compositions with improved exposure margin and defocus

latitude

INVENTOR(S):

Sato, Kenichiro Fuji Photo Film Co., Ltd., Japan PATENT ASSIGNEE(S):

SOURCE: Jpn. Kokai Tokkyo Koho, 81 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO. KIND DATE APPLICATION NO. JP 2000-402246 JP 2002202607 A2 20020719 20001228 JP 2000-402246 PRIORITY APPLN. INFO.: 20001228

MARPAT 137:116950 OTHER SOURCE(S):

398140-88-0P, tert-Butyl norbornenecarboxylate-maleic anhydride-2-methyl-2-adamantyl acrylate-norbornenelacton acrylate copolymer

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(far-UV pos. photoresists having sulfonium and iodonium photoacid generators with improved exposure margin and defocus latitude)

398140-88-0 CAPLUS RN

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, CN polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2Hcyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

IT 398141-14-5

RL: TEM (Technical or engineered material use); USES (Uses) (far-UV pos. photoresists having sulfonium and iodonium photoacid generators with improved exposure margin and defocus latitude)

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

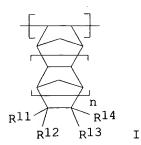
CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

$$\begin{array}{c} \text{O} \\ || \\ \text{HO-C-CH} = \text{CH}_2 \end{array}$$

GΙ



The resist compns. comprise (A) photoacid generators Q1Q2Q3S+X- [Q1-3 = (un)substituted phenyl; substituent = H, alkyl, alkoxy, OH, halo, SR; R = alkyl, aryl; X = RFSO3; RF = C.gtoreq.2-fluoroalkyl], X-Y1S+(Y2)Z1SZ2S+Y3Y4X- [Y1-4 = (un)substituted Ph (max. 2 substituents); Z1, Z2 = (un)substituted phenylene (max. 2 substituents); substituent, X = same as above], and Q4I+Q5X- [Q4, Q5 = (un)substituted phenyl; substituent, X = same as above] and (B) resins, which become alkali-sol. by acid decompn., comprising repeating units I (R11-14 = acid-decomposable group, H, halo, cyano, COOH, etc.; n = 0, 1), II (Z2 = O, NR41; R41 = H, OH, alkyl, haloalkyl, OSO2R42; R42 = alkyl, haloalkyl, etc.), and CH2CR91COX5BR92 (R91 = H, lower alkyl, halo, CN; X5 = O, S, NR93, NR93SO2; R93 = H, alkyl; B = single bond, linking group; R92 = H, alkyl, alkoxy, OH, etc.).

L30 ANSWER 12 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 12

ACCESSION NUMBER:

2002:538440 CAPLUS

DOCUMENT NUMBER:

137:116949

TITLE:

Storage-stable chemically amplified far-UV positive photoresists compositions with good sensitivity and no

aggregation

INVENTOR(S):

Sato, Kenichiro

PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 81 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

SOURCE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

IT 398140-88-0P

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses) (storage-stable far-UV pos. photoresist compns. in solvents with good

soly.)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

IT 398141-14-5

RL: TEM (Technical or engineered material use); USES (Uses) (storage-stable far-UV pos. photoresist compns. in solvents with good soly.)

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM .2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

GI

The resist compns., useful for contact hole formation in semiconductor ΑB device fabrication, comprise (A) photoacid generators, (B) resins, which become alkali-sol. by acid decompn., comprising repeating units I (R11-14 = acid-decomposable group, H, halo, cyano, COOH, etc.; n = 0, 1), II (22 = O, NR41; R41 = H, OH, alkyl, haloalkyl, OSO2R42; R42 = alkyl, haloalkyl, etc.), and CH2CR91COX5BR92 (R91 = H, lower alkyl, halo, CN; X5 = O, S, NR93, NR93SO2; R93 = H, alkyl; B = single bond, linking group; R92 = H, alkyl, alkoxy, OH, etc.), and (C) mixed solvents comprising 1st solvents of propylene glycol monoalkyl ether alkoxylates and 2nd solvents selected from propylene glycol monoalkyl ethers, alkyl lactates, and alkyl alkoxypropionates or, instead of the 2nd solvents, 3rd solvents selected from .gamma.-butyrolactone, ethylene carbonate, and propylene carbonate. The solvents may comprise .qtoreq.1 solvents selected from each of the 1st, 2nd, and 3rd solvent groups.

L30 ANSWER 13 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 13

ACCESSION NUMBER: 2002:539335 CAPLUS

DOCUMENT NUMBER: 137:101423

TITLE: Storage-stable chemically amplified far-UV positive

photoresist compositions suitable for half-tone

phase-shift photomasks

Sato, Kenichiro INVENTOR(S):

PATENT ASSIGNEE(S): Fuji Photo Film Co., Ltd., Japan SOURCE: Jpn. Kokai Tokkyo Koho, 80 pp.

CODEN: JKXXAF

DOCUMENT TYPE: Patent LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO. KIND DATE APPLICATION NO. DATE JP 2000-402244 JP 2002202605 A2 20020719 20001228 JP 2000-402244 20001228 PRIORITY APPLN. INFO.: OTHER SOURCE(S): MARPAT 137:101423

TΤ 398140-88-0P

> RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(storage-stable far-UV pos. photoresists contg. triphenylsulfonium photoacid generators for half-tone phase-shift photomasks)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

IT 398141-14-5

RL: TEM (Technical or engineered material use); USES (Uses) (storage-stable far-UV pos. photoresists contg. triphenylsulfonium photoacid generators for half-tone phase-shift photomasks)

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

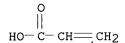
CRN 342648-11-7 CMF C13 H22 O2

CM 3

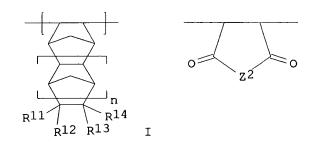
CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2



GΙ



The resist compns. comprise (A) photoacid generators [C6H5-1Rs4lS(C6H5-nRs6n)C6H5-mRs5m]+Xs- (Rs4, Rs5, Rs6 = alkyl, cycloalkyl, alkoxy, OH, etc.; l = 1-5; m, n = 0-5; Xs- = RSO3-; R = aliph. or arom. hydrocarbon group) and (B) resins comprising repeating units I (R11-14 = acid-decomposable group, H, halo, cyano, COOH, etc.; n = 0, 1), II (Z2 = 0, NR41; R41 = H, OH, alkyl, haloalkyl, OSO2R42; R42 = alkyl, haloalkyl, etc.), and CH2CR91COX5BR92 (R91 = H, lower alkyl, halo, CN; X5 = 0, S, NR93, NR93SO2; R93 = H, alkyl; B = single bond, linking group; R92 = H, alkyl, alkoxy, OH, etc.), wherein the resins become alkali-sol. by acid decompn.

II

L30 ANSWER 14 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 14

ACCESSION NUMBER:

2002:237124 CAPLUS

DOCUMENT NUMBER:

136:286589

TITLE:

Positive-working chemically amplified photoresist composition containing specific acid-sensitive resin

and specific nitrogen-containing compound for

semiconductor device fabrication

INVENTOR(S):

Fujimori, Toru; Kawabe, Yasumasa; Nakao, Hajime

PATENT ASSIGNEE(S): SOURCE:

Fuji Photo Film Co., Ltd., Japan Jpn. Kokai Tokkyo Koho, 92 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

Patent

LANGUAGE:

Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
JP 2002090987	A2	20020327	JP 2001-209543	20010710
US 2002155383	A1	20021024	US 2001-902793	20010712
PRIORITY APPLN. INFO.:	:	JP	2000-211642 A	20000712
OTHER SOURCE(S):	MA	RPAT 136:286589		

IT 398140-88-0P 398141-14-5P

RL: SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(resin in pos.-working photoresist compn.)

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

AB The title compn. contains a resin, which has an alicyclic hydrocarbon group, increasing the soly. rate in an alkali by reacting with an acid, a photo-acid generator, and a nitrogen-contg. compd., wherein the nitrogen-contg. compd. has group -C(=O)-N(OH)-. The compn. provides the improved line-edge roughness on the photoresist.

L30 ANSWER 15 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 15

ACCESSION NUMBER:

2002:904448 CAPLUS

DOCUMENT NUMBER:

138:9656

TITLE:

Positive photosensitive composition

INVENTOR(S):

Kodama, Kunihiko; Sato, Kenichiro; Fujimori, Toru

PATENT ASSIGNEE(S): Fuji Photo Film Co., Ltd., Japan

SOURCE:

Eur. Pat. Appl., 145 pp.

CODEN: EPXXDW

DOCUMENT TYPE:

Patent

LANGUAGE:

English

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PAT	ENT	NO.		KI	D	DATE			A.	PPLI	CATI	ON NO	ο.	DATE		
ΕP	1260	864		A	1	2002	1127		E	P 20	02-1	1516		2002	0522	
	R:	AT,	BE,	CH,	DE,	DK,	ES,	FR,	GB,	GR,	IT,	LI,	LU,	NL,	SE,	MC,
		IE,	SI,	LT,	LV,	FI,	RO,	MK,	CY,	AL,	TR					
													_			

JP 2001-152587 20010522 JP 2002351077 A2 20021204 JP 2002351079 A2 20021204 JP 2001-155897 20010524 20021204 JP 2001-159060 20010528 JP 2002351063 A2

PRIORITY APPLN. INFO.: JP 2001-152587 20010522 Α JP 2001~155897 Α 20010524

JP 2001-159060 Α 20010528 PT,

OTHER SOURCE(S):

MARPAT 138:9656

## 398140-71-1P 398140-88-0P 398141-14-5P 454470-67-8P

RL: PRP (Properties); SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses) (resin; pos photoresist compn. contg.)

RN 398140-71-1 CAPLUS

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-CN tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

2 CM

328087-76-9 CMF C21 H30 O2

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM :

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

RN 454470-67-8 CAPLUS

CN 2-Propenoic acid, 2-methyl-, 2-methyltricyclo[3.3.1.13,7]dec-2-yl ester, polymer with 7-oxo-6-oxabicyclo[3.2.1]oct-4-yl 2-propenoate and tetrahydro-5-oxo-3-furanyl 2-methyl-2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-83-5 CMF C10 H12 O4

CM 2

CRN 177080-67-0 CMF C15 H22 O2

130224-95-2 CRN CMF C8 H10 O4

AΒ A pos. photosensitive compn. comprises (A) a specific acid generator that generates an acid upon irradn. of an actinic ray or radiation, and (B) a resin that has a monocyclic or polycyclic alicyclic hydrocarbon structure and is decompd. by the action of an acid to increase soly. in an alkali developing soln.

REFERENCE COUNT:

THERE ARE 9 CITED REFERENCES AVAILABLE FOR THIS RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT

L30 ANSWER 16 OF 20 CAPLUS COPYRIGHT 2003 ACS

**DUPLICATE 16** 

ACCESSION NUMBER:

2002:119352 CAPLUS

DOCUMENT NUMBER:

136:175472

TITLE:

Positive photosensitive composition for

photofabrication using deep UV ray Kodama, Kunihiko; Aoai, Toshiaki

INVENTOR(S): PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan

SOURCE:

Eur. Pat. Appl., 120 pp.

CODEN: EPXXDW

DOCUMENT TYPE:

Patent

LANGUAGE:

English

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND DATI	Ξ	APPLICATION N	ο.	DATE		
EP 1179750	A1 2002	20213	EP 2001-11779	6	20010802		
R: AT, BE,	CH, DE, DK	, ES, FR,	GB, GR, IT, LI,	LU	, NL, SE,	MC,	PT,
IE, SI,	LT, LV, FI	, RO					
JP 2002122994	A2 2002	20426	JP 2001-18867	0	20010621		
US 2002051933	A1 2002	20502	US 2001-92169	1	20010806		
UŞ 6492091	B2 2002	21210					
PRIORITY APPLN. INFO	.:		JP 2000-240059	Α	20000808		
TT 200140 71 15 20	0140 00 00	200141 14	F-5				

IT

398140-71-1P 398140-88-0P 398141-14-5P RL: PRP (Properties); SPN (Synthetic preparation); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(resin; deep UV photofabrication pos. photoresist compn. contg.)

RN 398140-71-1 CAPLUS

CNBicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with .alpha.,.alpha.dimethylbicyclo[2.2.1]hept-5-ene-2-methanol, 2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

$$\bigcup_{c-o} \circ$$

CM 2

CRN 328087-76-9 CMF C21 H30 O2

$$\begin{array}{c|c} & Me \\ \hline \\ \hline \\ c-o-c \\ \hline \\ o & Me \\ \end{array}$$

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM I

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 CAPLUS

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM :

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

AB A pos. photosensitive compn. comprises: (A) a compd. generating an acid upon irradn. with one of an actinic ray and radiation; (B) a resin contg. a monocyclic or polycyclic alicyclic hydrocarbon structure and increasing the soly. to an alkali developer by the action of an acid; and (C) an onium salt of carboxylic acid. The present invention relates to a pos. photosensitive compn. for use in the prodn. process of a semiconductor such as IC, in the prodn. of a circuit board such as liq. crystal and

thermal head, and in other photofabrication processes.

13

REFERENCE COUNT:

THERE ARE 13 CITED REFERENCES AVAILABLE FOR THIS

RECORD. ALL CITATIONS AVAILABLE IN THE RE FORMAT

L30 ANSWER 17 OF 20 USPATFULL

ACCESSION NUMBER:

2002:279949 USPATFULL

TITLE:

Positive resist composition Fujimori, Toru, Shizuoka, JAPAN

INVENTOR(S):

Kawabe, Yasumasa, Shizuoka, JAPAN

Nakao, Hajime, Shizuoka, JAPAN

PATENT ASSIGNEE(S):

FUJI PHOTO FILM CO., LTD. (non-U.S. corporation)

NUMBER KIND DATE ------

PATENT INFORMATION: APPLICATION INFO.: US 2002155383 A1 20021024 US 2001-902793 A1 20010712 (9)

DATE NUMBER -----JP 2000-211642

PRIORITY INFORMATION:

20000712

DOCUMENT TYPE:

Utility

FILE SEGMENT:

APPLICATION

LEGAL REPRESENTATIVE:

SUGHRUE, MION, ZINN,, MACPEAK & SEAS, PLLC, 2100 Pennsylvania Avenue, NW, Washington, DC, 20037-3213

NUMBER OF CLAIMS: EXEMPLARY CLAIM:

1

LINE COUNT:

2009

CAS INDEXING IS AVAILABLE FOR THIS PATENT.

IT 398140-88-0P 398141-14-5P

(resin in pos.-working photoresist compn.)

RN398140-88-0 USPATFULL

Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, CN

polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-

cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

1

CM

CRN 249562-06-9 CMF C14 H20 O2

H2C== CH-C-

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398141-14-5 USPATFULL

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

AB A positive resist composition comprises: (A) a resin having an aliphatic cyclic hydrocarbon group and increasing the solubility to an alkali developer by the action of an acid; (B) a compound generating an acid upon irradiation with an actinic ray or radiation; and (C) a nitrogen-containing compound having in the molecule at least one partial structure represented by following formula (I). ##STR1##

## CAS INDEXING IS AVAILABLE FOR THIS PATENT.

L30 ANSWER 18 OF 20, USPATFULL

ACCESSION NUMBER: 2002:99037 USPATFULL

TITLE: Positive photosensitive composition

INVENTOR(S): Kodama, Kunihiko, Shizuoka, JAPAN

Aoai, Toshiaki, Shizuoka, JAPAN

PATENT ASSIGNEE(S): FUJI PHOTO FILM CO., LTD. (non-U.S. corporation)

	NUMBER	KIND	DATE	
PATENT INFORMATION:	US 2002051933 US 6492091	A1 B2	20020502	
APPLICATION INFO.:	US 2001-921691	A1	20010806	(9)

NUMBER DATE

PRIORITY INFORMATION: JP 2000-240059 20000808

DOCUMENT TYPE: Utility
FILE SEGMENT: APPLICATION

LEGAL REPRESENTATIVE: SUGHRUE, MION, ZINN, MACPEAK & SEAS, PLLC, 2100

Pennsylvania Avenue, N.W., Washington, DC, 20037

NUMBER OF CLAIMS:

20

EXEMPLARY CLAIM: LINE COUNT: 1 2260

CAS INDEXING IS AVAILABLE FOR THIS PATENT.

IT 398140-71-1P 398140-88-0P 398141-14-5P

(resin; deep UV photofabrication pos. photoresist compn. contg.)

RN 398140-71-1 USPATFULL

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1-methyl-1-

tricyclo[3.3.1.13,7]dec-1-ylethyl ester, polymer with

.alpha.,.alpha.-dimethylbicyclo[2.2.1]hept-5-ene-2-methanol,

2,5-furandione and tetrahydro-5-oxo-3-furanyl bicyclo[2.2.1]hept-5-ene-2-

carboxylate (9CI) (CA INDEX NAME)

CM 1

CRN 398140-70-0 CMF C12 H14 O4

CM 2

CRN 328087-76-9 CMF C21 H30 O2

CM 3

CRN 22497-08-1 CMF C10 H16 O

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 398140-88-0 USPATFULL

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylethyl ester, polymer with 2,5-furandione, hexahydro-2-oxo-3,5-methano-2H-cyclopenta[b]furan-6-yl 2-propenoate and 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 242129-35-7 CMF C11 H12 O4

CM 3

CRN 154970-45-3 CMF C12 H18 O2

CM 4

CRN 108-31-6

RN 398141-14-5 USPATFULL

CN Bicyclo[2.2.1]hept-5-ene-2-carboxylic acid, 1,1-dimethylpropyl ester, polymer with 2,5-furandione, 1-methyl-1-(4-methylcyclohexyl)ethyl 2-propenoate and 2-propenoic acid (9CI) (CA INDEX NAME)

CM 1

CRN 398140-58-4 CMF C13 H20 O2

CM 2

CRN 342648-11-7 CMF C13 H22 O2

CM 3

CRN 108-31-6 CMF C4 H2 O3

CM 4

CRN 79-10-7 CMF C3 H4 O2

AB A positive photosensitive composition comprises: (A) a compound generating an acid upon irradiation with one of an actinic ray and radiation; (B) a resin containing a monocyclic or polycyclic alicyclic hydrocarbon structure and increasing the solubility to an alkali developer by the action of an acid; and (C) an onium salt of carboxylic acid.

CAS INDEXING IS AVAILABLE FOR THIS PATENT.

L30 ANSWER 19 OF 20 CAPLUS COPYRIGHT 2003 ACS DUPLICATE 17

ACCESSION NUMBER: 2001:496392 CAPLUS

DOCUMENT NUMBER: 135:99845

TITLE: Positive-working photoresist composition containing

alkali-soluble polymer with silyl group

INVENTOR(S): Mizutani, Kazuyoshi; Yanami, Shoichiro

PATENT ASSIGNEE(S): Fuji Photo Film Co., Ltd., Japan SOURCE: Jpn. Kokai Tokkyo Koho, 52 pp.

CODEN: JKXXAF

DOCUMENT TYPE: Patent LANGUAGE: Japanese

FAMILY ACC. NUM. COUNT: 2

PATENT INFORMATION:

7/10/01

PATENT NO. KIND DATE APPLICATION NO. DATE

JP 2001188349 A2 200010710 JP 2000-303876 20001003

PRIORITY APPLN. INFO.: JP 1999-298606 A 19991020

IT 336609-27-9P 348129-27-1P 348129-35-1P

349477-30-1P

RL: PNU (Preparation, unclassified); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(pos.-working photoresist compn. contg. binder with silyl group, acid generator, org. base, and surfactant)

RN 336609-27-9 CAPLUS

CN 2-Propenoic acid, ethoxymethyl ester, polymer with 2,5-furandione and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 101181-06-0 CMF C6 H10 O3

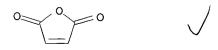
 $\begin{array}{c} \text{O} \\ \parallel \\ \text{EtO-CH$_2$-O-C-CH$_{$==$}$ CH$_2} \end{array}$ 

CM 2

CRN 762-72-1 CMF C6 H14 Si

Me<sub>3</sub>Si-CH<sub>2</sub>-CH=CH<sub>2</sub>

CRN 108-31-6 CMF C4 H2 O3



RN 348129-27-1 CAPLUS

CN 2-Propenoic acid, 2-methyltricyclo[3.3.1.13,7]dec-2-yl ester, polymer with 2,5-furandione and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2 ·

CRN 762-72-1 CMF C6 H14 Si

/

 $Me_3Si-CH_2-CH=CH_2$ 

CM 3

CRN 108-31-6 CMF C4 H2 O3

RN 348129-35-1 CAPLUS

CN 2-Propenoic acid, butyl ester, polymer with 2,5-furandione, 2-methyltricyclo[3.3.1.13,7]dec-2-yl 2-propenoate and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9

CRN 762-72-1 CMF C6 H14 Si

 ${\tt Me3Si-CH2-CH} = {\tt CH2}$ 

CM 3

CRN 141-32-2 CMF C7 H12 O2

$$\begin{array}{c} \text{O} \\ \parallel \\ \text{n-BuO-C-CH-CH----} \end{array}$$

CM 4

CRN 108-31-6 CMF C4 H2 O3

RN 349477-30-1 CAPLUS

CN 2-Butenedioic acid, 1,1-dimethylethyl methyl ester, polymer with 2,5-furandione and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 349477-29-8 CMF C9 H14 O4

CM 2

CRN 762-72-1 CMF C6 H14 Si

 $Me_3Si-CH_2-CH=-CH_2$ 

CM 3

CRN 108-31-6 CMF C4 H2 O3

The compn. comprises (A) a binder resin having a repeating unit bearing a AB structure (CH2) nSiR1R2R3 (R1-3 = alkyl, haloalkyl, halo, alkoxy, trialkylsilyl, trialkylsilyloxy; n = 0, 1) and a repeating unit bering a group which decomps. by the action of an acid and increases the soly. in an alk. developer at the side chain, (B) a compd. generating an acid by the action of an actinic ray or radiation, (C) a solvent dissolving A and B, (D) an org. base compd., (E) .gtoreq.1 surfactant selected from a fluorosurfactant, a silicone surfactant, and a nonionic surfactant. compn. shows high resoln. and gives patterns with rectangular cross section and is useful for manuf. of semiconductor device.

L30 ANSWER 20 OF 20 CAPLUS COPYRIGHT 2003 ACS

DUPLICATE 18

ACCESSION NUMBER:

2001:496391 CAPLUS

DOCUMENT NUMBER:

135:99844

TITLE:

Positive-working photoresist composition containing

vinyl copolymer with silyl group

INVENTOR(S):

Mizutani, Kazuyoshi; Yasunami, Shouichiro

PATENT ASSIGNEE(S):

Fuji Photo Film Co., Ltd., Japan

SOURCE:

Jpn. Kokai Tokkyo Koho, 42 pp.

CODEN: JKXXAF

DOCUMENT TYPE:

LANGUAGE:

Patent Japanese

FAMILY ACC. NUM. COUNT:

PATENT INFORMATION:

PATENT NO.	KIND	DATE	APPLICATION NO.	DATE
JP 2001188348	A2	20010710	JP 2000-303875	20001003
PRIORITY APPLN. INFO.	:		JP 1999-298606 A	19991020

IT 336609-27-9P 348129-27-1P

RL: PNU (Preparation, unclassified); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses)

(pos.-working photoresist compn. contg. vinyl copolymer with silyl group and acid generator)

336609-27-9 CAPLUS RN

2-Propenoic acid, ethoxymethyl ester, polymer with 2,5-furandione and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 101181-06-0 CMF C6 H10 O3

$$\begin{array}{c|c}
 & O \\
 & \parallel \\
 & \text{Eto-} CH_2-O-C-CH- CH_2
\end{array}$$

CRN 762-72-1 CMF C6 H14 Si

 $Me_3Si-CH_2-CH=CH_2$ 

CM 3

CRN 108-31-6 CMF C4 H2 O3

RN 348129-27-1 CAPLUS

CN 2-Propenoic acid, 2-methyltricyclo[3.3.1.13,7]dec-2-yl ester, polymer with 2,5-furandione and trimethyl-2-propenylsilane (9CI) (CA INDEX NAME)

CM 1

CRN 249562-06-9 CMF C14 H20 O2

CM 2

CRN 762-72-1 CMF C6 H14 Si

 $Me_3Si-CH_2-CH \longrightarrow CH_2$ 

CM 3

CRN 108-31-6 CMF C4 H2 O3

GΤ

The photoresist compn. comprises (A) a binder resin whose soly. in an alk. developer increases by the action of an acid and having repeating units CH2CH[(CH2)nSiR1R2R3] (R1-3 = alkyl, haloalkyl, halo, alkoxy, trialkylsilyl, trialkylsilyloxy; n = 0,1) CH2CY(LCO2Q) (Y = H, Me, cyano, Cl; L = bond, divalent linkage,; Q = C5-20 tert-alkyl, alkoxymethyl, alkoxyethyl, isobornyl) and I (Z = O, NR3; R3 = H, OH, alkyl, OSO2R4; R4 = alkyl, trihalomethyl), (B) a compd. generating an acid by the action of an actinic ray or radiation, and (C) a solvent dissolving A and B. The compn. shows high resoln., less disappearance of rough pattern at the resoln. limit, and is useful for manuf. of semiconductor devices.